Regarding the change of names mentioned in the document, such as Mitsubishi Electric and Mitsubishi XX, to Renesas Technology Corp.

The semiconductor operations of Hitachi and Mitsubishi Electric were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Mitsubishi Electric, Mitsubishi Electric Corporation, Mitsubishi Semiconductors, and other Mitsubishi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

Note: Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

Renesas Technology Corp. Customer Support Dept. April 1, 2003



8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

DESCRIPTION

The M5M5W816 is a family of low voltage 8-Mbit static RAMs organized as 524288-words by 16-bit, fabricated by Mitsubishi's high-performance 0.18µm CMOS technology.

The M5M5W816 is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

M5M5W816WG is packaged in a CSP (chip scale package), with the outline of 7.5mm x 8.5mm, ball matrix of 6 x 8 (48ball) and ball pitch of 0.75mm. It gives the best solution for a compaction of mounting area as well as flexibility of wiring pattern of printed circuit boards.

FEATURES

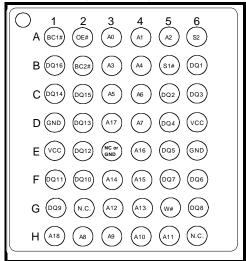
- Single 2.7~3.6V power supply
- Small stand-by current: 0.1µA (2V, typ.)
- No clocks, No refresh
- Data retention supply voltage =2.0V
- All inputs and outputs are TTL compatible.
- Easy memory expansion by S1#, S2, BC1# and BC2#
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE prevents data contention in the I/O bus
- Process technology: 0.18µm CMOS
- Package: 48ball 7.5mm x 8.5mm CSP

Version,		-		Stand-by current (µA)						Activ e
Operating Part name	Power	Access time	* Ty pical(3.0V)		Ratings (max.@ Vcc=3.6V)				current	
temperature		Supply	max.	25°C	40°C	25°C	40°C	70°C	85°C	lcc1 *(3.0V, typ.)
	M5M5W816WG -55HI		55ns							30mA
I-version	M5M5W816WG -70HI	2.7 ~ 3.6V	70ns	0.5	1.0	5.0	8.0	20	40	(10MHz) 5mA
-40 ~ +85°C	M5M5W816WG -85HI		85ns							(1MHz)

^{*} Typical parameter indicates the value for the center of distribution, and is not 100% tested.

PIN CONFIGURATION

(TOP VIEW)



Outline : 48F7Q NC : No Connection

*Don't connect E3 ball to voltage level more than 0V.

Pin	Function					
A0 ~ A18	Address input					
DQ1 ~ DQ16	Data input / output					
S1#	Chip select input 1					
S2	Chip select input 2					
W#	Write control input					
OE#	Output enable input					
BC1#	Lower Byte (DQ1 ~ 8)					
BC2#	Upper Byte (DQ9 ~ 16)					
Vcc	Power supply					
GND	Ground supply					



8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

FUNCTION

The M5M5W816WG is organized as 524288-words by 16-bit. These devices operate on a single +2.7~3.6V power supply, and are directly TTL compatible to both input and output. Its fully static circuit needs no clocks and no refresh, and makes it useful.

The operation mode are determined by a combination of the device control inputs BC1#, BC2#, S1#, S2, W# and OE#. Each mode is summarized in the function table.

A write operation is executed whenever the low level W# overlaps with the low level BC1# and/or BC2# and the low level S1# and the high level S2. The address(A0~A18) must be set up before the write cycle and must be stable during the entire cycle.

A read operation is executed by setting W# at a high level and OE# at a low level while BC1# and/or BC2# and S1# and S2 are in an active state(S1#=L,S2=H).

When setting BC1# at the high level and other pins are in an active stage, upper-byte are in a selectable mode in which both reading and writing are enabled, and lower-byte are in a non-selectable mode. And when setting BC2# at a high level and other pins are in an active stage, lower-byte are in a selectable mode and upper-byte are in a non-selectable mode.

When setting BC1# and BC2# at a high level or S1# at a high level or S2 at a low level, the chips are in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips and memory expansion by BC1#, BC2# and S1#, S2.

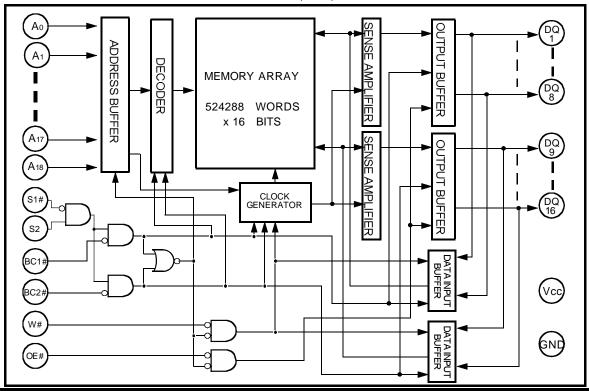
The power supply current is reduced as low as $0.1\mu A(25^{\circ}C$, typical), and the memory data can be held at +2.0V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.

FUNCTION TABLE

S1#	S2	BC1#	BC2#	W#	OE#	Mode	DQ1~8	DQ9~16	lcc
Н	L	Х	Χ	Χ	Χ	Non selection	High-Z	High-Z	Standby
L	L	Χ	Χ	Χ	Χ	Non selection	High-Z	High-Z	Standby
Н	Ι	Χ	Χ	Χ	Χ	Non selection	High-Z	High-Z	Standby
Χ	Χ	Τ	Н	Χ	Χ	Non selection	High-Z	High-Z	Standby
L	Ι	L	Н	L	Χ	Write	Din	High-Z	Activ e
L	Η	L	Н	Н	L	Read	Dout	High-Z	Activ e
L	Ι	L	Н	Η	Н		High-Z	High-Z	Activ e
L	Н	Н	L	L	Χ	Write	High-Z	Din	Activ e
L	Η	Н	L	Н	L	Read	High-Z	Dout	Activ e
L	Н	Н	L	Н	Н		High-Z	High-Z	Activ e
L	Н	L	L	L	Χ	Write	Din	Din	Activ e
L	Н	L	L	Н	L	Read	Dout	Dout	Activ e
L	Н	L	L	Н	Н		High-Z	High-Z	Activ e

(note1) "H" and "L" in this table mean VIH and VIL, respectively . (note2) "X" in this table should be "H" or "L".

BLOCK DIAGRAM





8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Units
Vcc	Supply voltage	With respect to GND	-0.3* ~ +4.6	
Vı	Input voltage	With respect to GND	-0.3* ~ Vcc + 0.3 (max. 4.6V)	V
Vo	Output voltage	With respect to GND	0 ~ Vcc	
Pd	Power dissipation	Ta= 25°C	700	mW
Та	Operating temperature		- 40 ~ +85	°C
Tstg	Storage temperature		- 65 ~ + 150	°C

^{* -3.0}V in case of AC (Pulse width \leq 30ns)

DC ELECTRICAL CHARACTERISTICS

(Vcc=2.7 ~ 3.6V, unless otherwise noted)

C male of	Danamatan	O and distant		Limits			
Symbol	Parameter	Conditions		Min	Тур	Max	Units
ViH	High-level input voltage			2.2		Vcc+0.2V	
VIL	Low-lev el input v oltage			-0.2 *		0.6	
Vон	High-level output voltage	Iон= -0.5mA		2.4			V
Vol	Low-level output voltage	IoL=2mA				0.4	
lı	Input leakage current	Vı=0 ~ Vcc				±1	
lo	Output leakage current	BC1# and BC2# =VIH or S1# =VIH or S2=VIL or OE# =VIH, VI/O=0 ~ Vcc				±1	μΑ
land	Active supply current	BC1# and BC2# ≤ 0.2V, S1# ≤ 0.2V, S2 ≥ Vcc-0.2V		-	30	50	
Icc1	(AC,MOS level)	other inputs < 0.2 v or < 2 vcc-0.2 v	f= 1MHz	ı	5	15	
	Active supply current	BC1# and BC2#=VIL, S1#=VIL, S2=VIH other pins =VIH or VIL	f= 10MHz	-	30	50	mA
Icc2	(AC,TTL level)	Output - open (duty 100%)	f= 1MHz	ı	5	15	
		(1) S1# ≥ Vcc - 0.2V, S2 > Vcc - 0.2V.	~ +25°C	ı	0.5	5	
lcc3	Stand by supply current	other inputs = $0 \sim Vcc$ (2) S2 $\leq 0.2V$,	~ +40°C	-	1.0	8	
1003	(AC,MOS level)	other inputs = $0 \sim Vcc$ (3) BC1# and BC2# $\geq Vcc - 0.2V$	~ +70°C	-	-	20	μA
		$S1# \le 0.2V$, $S2 \ge Vcc - 0.2V$ other inputs = 0 ~ Vcc	~ +85°C	-	-	40	
lcc4	Stand by supply current (AC,TTL level)	BC1# and BC2# =VIH or S1# =VIH or S2 =VIL Other inputs= 0 ~ Vcc		-	-	2	mA

Note 1: Direction for current flowing into IC is indicated as positive (no mark).

CAPACITANCE

(Vcc=2.7 ~ 3.6V, unless otherwise noted)

Symbo Parameter	Parameter	Parameter Conditions		Limits		
	Conditions	Min	Тур	Max	Units	
Сі	Input capacitance	V=GND, V=25mVrms, f=1MHz			10	ρF
Со	Output capacitance	Vo=GND,Vo=25mVrms, f=1MHz			10	рι



^{* -1.0}V in case of AC (Pulse width \leq 30ns)

Note 2: Typical parameter indicates the value for the center of distribution at 3.0V, and is not 100% tested.

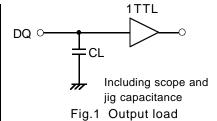
8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

AC ELECTRICAL CHARACTERISTICS

(Vcc=2.7 ~ 3.6V, unless otherwise noted)

(1) TEST CONDITIONS

Supply voltage	2.7~3.6V				
Input pulse	V _{IH} =2.4V, V _{IL} =0.4V				
Input rise time and fall time	5ns				
Reference level	VoH=VoL=1.5V	Transition is measured ±200mV from steady state voltage.(for ten,tdis)			
Output loads	Fig.1,CL=30pF CL=5pF (fo	or ten,tdis)			



(2) READ CYCLE

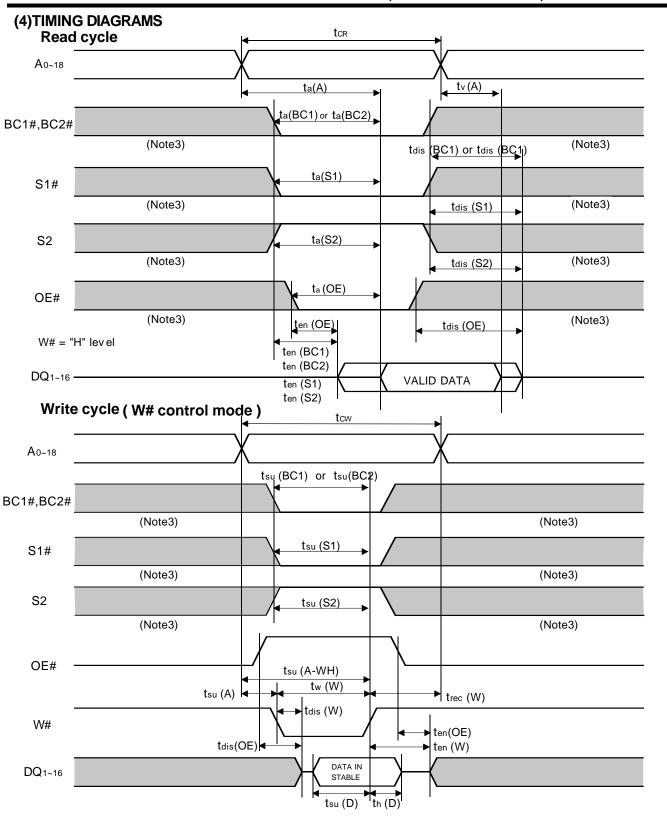
	_			Lim	nits			
Symbol	Parameter	55	55HI		70HI		85HI	
,		Min	Max	Min	Max	Min	Max	
tcr	Read cycle time	55		70		85		ns
ta(A)	Address access time		55		70		85	ns
ta(S1)	Chip select 1 access time		55		70		85	ns
ta(S2)	Chip select 2 access time		55		70		85	ns
ta(BC1)	Byte control 1 access time		55		70		85	ns
ta(BC2)	Byte control 2 access time		55		70		85	ns
ta(OE)	Output enable access time		30		35		45	ns
tdis(S1)	Output disable time after S1# high		20		25		30	ns
tdis(S2)	Output disable time after S2 low		20		25		30	ns
tdis(BC1)	Output disable time after BC1# high		20		25		30	ns
tdis(BC2)	Output disable time after BC2# high		20		25		30	ns
tdis(OE)	Output disable time after OE# high		20		25		30	ns
ten(S1)	Output enable time after S1# low	10		10		10		ns
ten(S2)	Output enable time after S2 high	10		10		10		ns
ten(BC1)	Output enable time after BC1# low	5		5		5		ns
ten(BC2)	Output enable time after BC2# low	5		5		5		ns
ten(OE)	Output enable time after OE# low	5		5		5		ns
t∨(A)	Data valid time after address	10		10		10		ns

(3) WRITE CYCLE

					Lim	nits		
Symbol	Parameter	55I	НI	70	HI	85	HI	Units
- J	, a.a.nete.	Min	Max	Min	Max	Min	Max	
tcw	Write cycle time	55		70		85		ns
t _w (W)	Write pulse width	45		55		60		ns
tsu(A)	Address setup time	0		0		0		ns
tsu(A-WH)	Address setup time with respect to W#	50		65		70		ns
tsu(BC1)	Byte control 1 setup time	50		65		70		ns
tsu(BC2)	By te control 2 setup time	50		65		70		ns
tsu(S1)	Chip select 1 setup time	50		65		70		ns
tsu(S2)	Chip select 2 setup time	50		65		70		ns
tsu(D)	Data setup time	30		35		45		ns
th(D)	Data hold time	0		0		0		ns
trec(W)	Write recovery time	0		0		0		ns
tdis(W)	Output disable time from W# low		20		25		30	ns
tdis(OE)	Output disable time from OE# high		20		25		30	ns
ten(W)	Output enable time from W# high	5		5		5		ns
ten(OE)	Output enable time from OE# low	5		5		5		ns

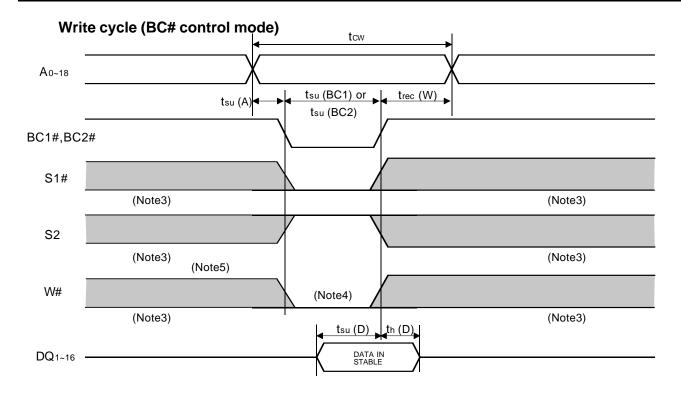


8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM





8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM



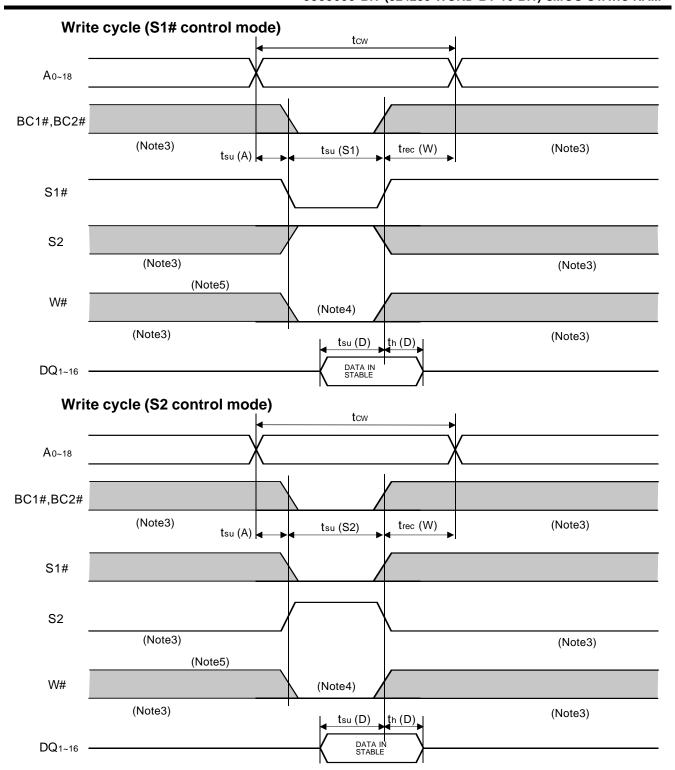
Note 3: Hatching indicates the state is "don't care".

Note 4: A Write occurs during S1# low, S2 high overlaps BC1# and/or BC2# low and W# low.

Note 5: When the falling edge of W# is simultaneously or prior to the falling edge of BC1# and/or BC2# or the falling edge of S1# or rising edge of S2, the outputs are maintained in the high impedance state.

Note 6: Don't apply inverted phase signal externally when DQ pin is in output mode.

8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM



8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

POWER DOWN CHARACTERISTICS

(1) ELECTRICAL CHARACTERISTICS

0 1 1	Б.,				Limits		
Symbol	Parameter	Test conditions		Min	Тур	Max	Units
Vcc (PD)	Power down supply voltage		2.0			V	
VL(BC)	Byte control input BC1# &	2.2V ≤ Vcc(PD)		2.2			
VI (BC) Byte control input BC1# & BC2#		2.0V ≤ Vcc(PD) ≤ 2.2V			Vcc(PD)		V
Vivos		2.2V ≤ Vcc(PD)					
VI (S1)	VI (S1) Chip select input S1#	2.0V ≤ Vcc(PD) ≤ 2.2V		Vcc(PD)		V	
VI (S2)	Chip select input S2					0.2	
		Vcc=2.0V (1) S1# ≥ Vcc - 0.2V,	~ +25°C	-	0.1	1.5	
Icc (PD)	Power down	other inputs = 0 ~ Vcc (2) S2 ≤ 0.2V,	~ +40°C	-	0.2	3	
supply curre	supply current	other inputs = 0 ~ Vcc (3) BC1# and BC2# ≥ Vcc - 0.2V	~ +70°C	-	-	15	μΑ
		S1# ≤ 0.2V, S2 ≥ Vcc - 0.2V other inputs = 0 ~ Vcc	~ +85°C	-	-	30	

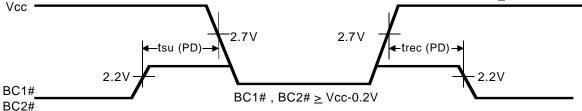
Note 7: Typical parameter of lcc(PD) indicates the value for the center of distribution, and is not 100% tested.

(2) TIMING REQUIREMENTS

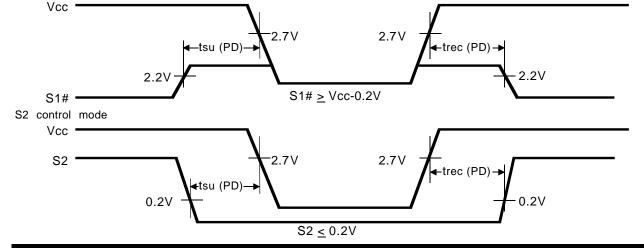
	_			11.2		
Symbol	Parameter	Test conditions	Min	Тур	Max	Units
tsu (PD)	Power down set up time		0			ns
trec (PD)	Power down recovery time		5			ms

(3) TIMING DIAGRAM

BC# control mode On the BC# control mode, the level of S1# and S2 must be fixed at S1#, S2 \geq Vcc-0.2V or S2 \leq 0.2V.



S1# control mode On the S1# control mode, the level of S2 must be fixed at S2 \geq Vcc-0.2V or S2 \leq 0.2V.



Keep safety first in your circuit designs!

Mitsubishi Electric Corporation puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage. Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of non-flammable material or (iii) prevention against any malfunction or mishap.

Notes regarding these materials

These materials are intended as a reference to assist our customers in the selection of the Mitsubishi semiconductor product best suited to the customer's application; they do not convey any license under any intellectual property rights, or any other rights, belonging to Mitsubishi Electric Corporation or a third party.

Mitsubishi Electric Corporation assumes no responsibility for any damage, or infringement of any third-party's rights, originating in the use of any product data, diagrams, charts, programs, algorithms, or circuit application examples contained in these materials.

All information contained in these materials, including product data, diagrams, charts, programs and algorithms represents information on products at the time of publication of these materials, and are subject to change by Mitsubishi Electric Corporation without notice due to product improvements or other reasons. It is therefore recommended that customers contact Mitsubishi Electric Corporation or an authorized Mitsubishi Semiconductor product distributor for the latest product information before purchasing a product listed herein.

The information described here may contain technical inaccuracies or typographical errors. Mitsubishi Electric Corporation assumes no responsibility for any damage, liability, or other loss rising from these inaccuracies or errors.

Please also pay attention to information published by Mitsubishi Electric Corporation by various means, including the Mitsubishi Semiconductor home page (http://www.mitsubishichips.com).

When using any or all of the information contained in these materials, including product data, diagrams, charts, programs, and algorithms, please be sure to evaluate all information as a total system before making a final decision on the applicability of the information and products. Mitsubishi Electric Corporation assumes no responsibility for any damage, liability or other loss resulting from the information contained herein.

Mitsubishi Electric Corporation semiconductors are not designed or manufactured for use in a device or system that is used under circumstances in which human life is potentially at stake. Please contact Mitsubishi Electric Corporation or an authorized Mitsubishi Semiconductor product distributor when considering the use of a product contained herein for any specific purposes, such as apparatus or systems for transportation, vehicular, medical, aerospace, nuclear, or undersea repeater use.

The prior written approval of Mitsubishi Electric Corporation is necessary to reprint or reproduce in whole or in part these materials.

If these products or technologies are subject to the Japanese export control restrictions, they must be exported under a license from the Japanese government and cannot be imported into a country other than the approved destination.

Any diversion or reexport contrary to the export control laws and regulations of Japan and/or the country of destination is prohibited.

Please contact Mitsubishi Electric Corporation or an authorized Mitsubishi Semiconductor product distributor for further details on these materials or the products contained therein.

